

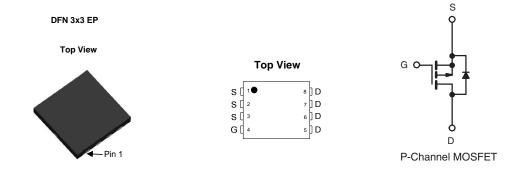
P-Channel 60 V (D-S) 175 °C MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	-60				
$R_{DS(on)}(\Omega)$ at $V_{GS} = -10 \text{ V}$	0.0210				
$R_{DS(on)}(\Omega)$ at $V_{GS} = -4.5 \text{ V}$	0.0288				
I _D (A)	-36				
Configuration	Single				
Package	DFN 3X3				

FEATURES

- TrenchFET® power MOSFET
- 100 % R_g and UIS tested





ABSOLUTE MAXIMUM RATING	S (T _C = 25 °C, unles	s otherwise noted	1)		
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	-60	V	
Gate-Source Voltage	V _{GS}	± 20			
Continuous Drain Current	T _C = 25 °C	1	-36		
	T _C = 125 °C	I _D	-21		
Continuous Source Current (Diode Conducti	I _S	-60	Α		
Pulsed Drain Current ^b		I _{DM}	-100		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	-36		
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	64.8	mJ	
Maximum Power Dissipation ^b	T _C = 25 °C	Р	68	W	
	T _C = 125 °C	- P _D	22	VV	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +175	°C	
Soldering Recommendations (Peak Tempera		260			

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	LIMIT	UNIT		
Junction-to-Ambient	PCB Mount ^c	R_{thJA}	68	°C/W		
Junction-to-Case (Drain)		R_{thJC}	2.2	C/VV		

Notes

- a. Package limited.
- b. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- c. When mounted on 1" square PCB (FR4 material).
- d. For DFN3X3, the end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.



SPECIFICATIONS (T _C = 25 °C, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$, $I_D = -250 \mu A$		-60	-	-	V
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$		-2.0	-2.5	V
Gate-Source Leakage	I _{GSS}	V _{DS} =	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$		-	± 100	nA
		$V_{GS} = 0 V$	V _{DS} = -60 V	1	-	-1	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V _{DS} = -60 V, T _J = 125 °C	-	-	-50	μΑ
		$V_{GS} = 0 V$	V _{DS} = -60 V, T _J = 175 °C	1	-	-150	
On-State Drain Current ^a	I _{D(on)}	$V_{GS} = -10 \text{ V}$	$V_{DS} \ge -5 V$	-30	-	-	Α
		V _{GS} = -10 V	I _D = -10 A	1	0.0210	-	Ω
Drain-Source On-State Resistance a	D	V _{GS} = -10 V	I _D = -10 A, T _J = 125 °C	1	0.0409	-	
Diani-Source On-State nesistance	R _{DS(on)}	$V_{GS} = -10 \text{ V}$	I _D = -10 A, T _J = 175 °C	1	0.0504	-	
		$V_{GS} = -4.5 \text{ V}$	I _D = -5 A	-	0.0288	-	
Forward Transconductance b	9 _{fs}	V _{DS} =	-15 V, I _D = -10 A	1	26	-	S
Dynamic ^b							
Input Capacitance	C _{iss}		_{GS} = 0 V V _{DS} = -25 V, f = 1 MHz	ı	2600	3400	pF
Output Capacitance	C _{oss}	$V_{GS} = 0 V$		ı	310	450	
Reverse Transfer Capacitance	C _{rss}			1	200	275	
Total Gate Charge ^c	Qg			1	65	100	nC
Gate-Source Charge ^c	Q_{gs}	$V_{GS} = -10 \text{ V}$	$V_{DS} = -30 \text{ V}, I_{D} = -5 \text{ A}$	1	9.5	-	
Gate-Drain Charge ^c	Q_{gd}			1	19	-	
Gate Resistance	R _g	f = 1 MHz		0.50	1.19	1.80	Ω
Turn-On Delay Time ^c	t _{d(on)}	$V_{DD} = -30 \text{ V, } R_L = 6 \Omega$ $I_D \cong -5 \text{ A, } V_{GEN} = -10 \text{ V, } R_g = 1 \Omega$		-	15	25	ns
Rise Time ^c	t _r			-	5	10	
Turn-Off Delay Time ^c	t _{d(off)}			-	40	75	
Fall Time ^c	t _f			1	6	12	
Source-Drain Diode Ratings and Characteristics ^b							
Pulsed Current ^a	I _{SM}			=	-	-100	Α
Forward Voltage	V _{SD}	I _F = -10 A, V _{GS} = 0 V		-	-0.80	-1.2	V

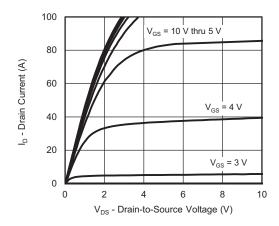
Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- $\ \ \, \text{c. Independent of operating temperature.}$

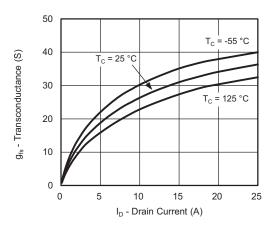
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



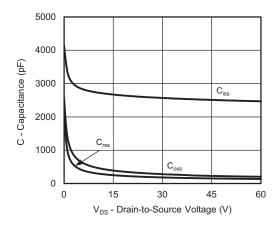
TYPICAL CHARACTERISTICS ($T_A = 25$ °C, unless otherwise noted)



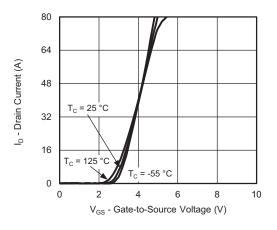
Output Characteristics



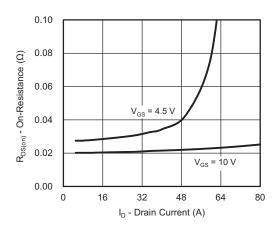
Transconductance



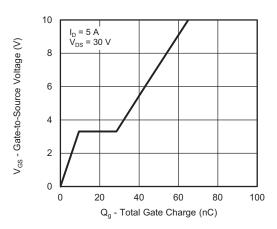
Capacitance



Transfer Characteristics



On-Resistance vs. Drain Current

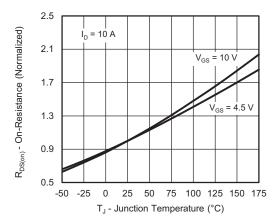


Gate Charge

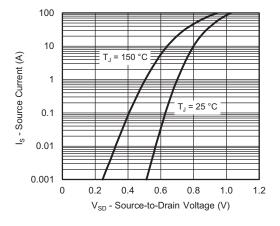
4



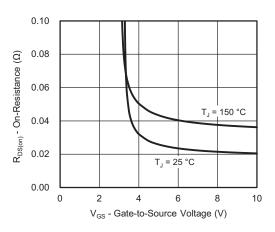
TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)



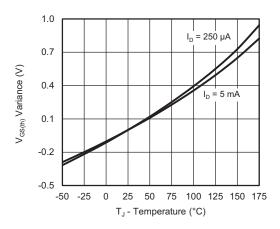
On-Resistance vs. Junction Temperature



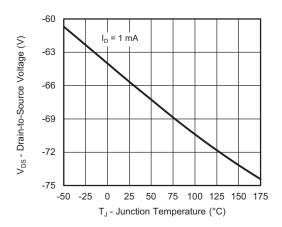
Source Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage



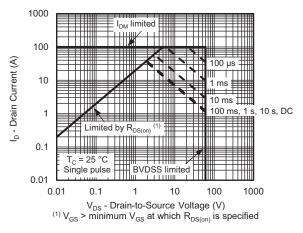
Threshold Voltage



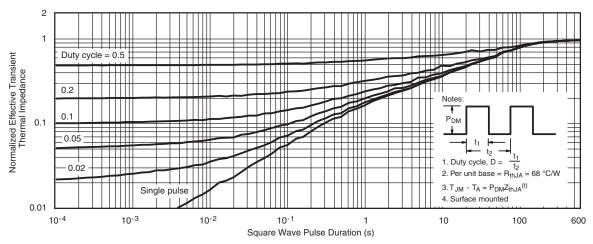
Drain-Source Breakdown vs. Junction Temperature



THERMAL RATINGS ($T_C = 25$ °C, unless otherwise noted)



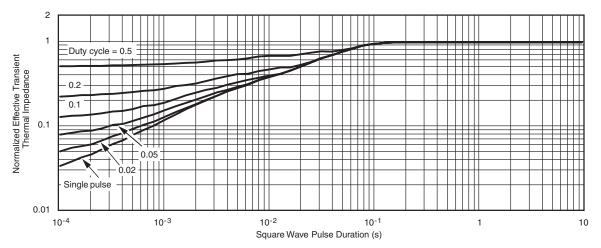
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS (T_C = 25 °C, unless otherwise noted)

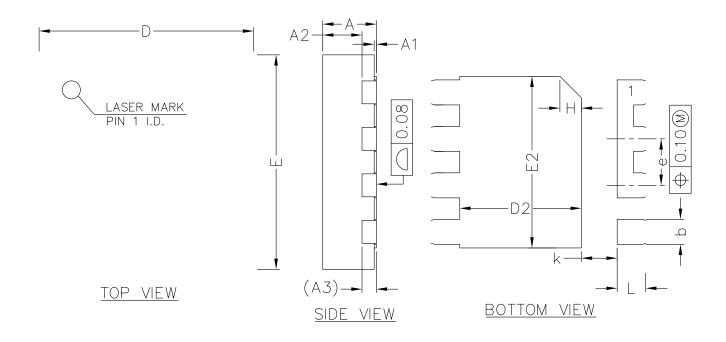


Normalized Thermal Transient Impedance, Junction-to-Case

Note

- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)
 - Normalized Transient Thermal Impedance Junction-to-Case (25 °C) are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.







COMMON DIMENSIONS
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
А	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
А3	0.20REF			
b	0.30	0.35	0.40	
D	2.90	3.00	3.10	
Ε	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	



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